



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

EUROFINS EAG ENGINEERING SCIENCE, LLC  
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ELECTRICAL

Valid To: February 28, 2026

Certificate Number: 2797.12

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following types of tests on integrated circuits and electronic components:

<u>Test(s):</u>	<u>Test Method(s)<sup>1,2</sup>:</u>
<b><u>Electrical</u></b>	
Voltage Stress	
Rise / Fall Time (2 to 10) ns Rise / Delay Time (130 to 170) ns  Current: (0.06-5.86) A	JEDEC JS-001, JESD22-A114; MIL-STD 883 TM 3015; AEC-Q100-002, AEC-Q101-001; SOP61, WIF1 Test – Human Body Mod
Frequency (11 to 16) MHz  Pin Capacity: 100V to 400V Current: (8.0) A	JEDEC JESD22-A115; AEC-Q100-003, AEC-Q101-002; SOP61, WIF1 Test – Machine Model
Pin Capacity (100 to 300) mA (70 to 125) °C	JEDEC JESD78; AEC-Q100-004; SOP61, WIF1 Test –IC Latch-Up
Rise / Fall Time < 400 ps Peak Current (1.4 to 27.9) A  Pin Capacity: 125V to 1 kV	JEDEC JESD22-C101, JEDEC JS-002; AEC-Q100-011, AEC-Q101-005; SOP61, WIF1 Test – Field Induced; Charged Device Model

<b><u>Test(s):</u></b>	<b><u>Test Method(s) <sup>1,2:</sup></u></b>
<b><u>Environmental</u></b>	
Thermal Stress	
HTOL (High Temperature Operating Life)  (85 ~ 150) °C ± 3 °C (1 to 4) V, (0 to 52) A	JESD22-A108; SOP52, WIF20
HTSL (High Temperature Storage Life)  150 °C (- 0 to 10) °C	JESD22-A103; SOP52, WIF15
THB (Temperature Humidity Bias)  85 °C ± 2 °C, 85 % ± 5 %RH	JESD22-A101; SOP52, WIF10
HAST (Highly Accelerated Stress Test)  110 °C ± 2°C, 17.7 psia 130 ± 2°C, 33.3 psia 85 % ± 5 %RH	JESD22-A110; SOP52, WIF13
TMCL – Temperature Cycling  Condition A-N (air to air) (-65 to 150) °C (10 to 15) min Dwell <10 s transfer	JESD22-A104; MIL-STD 883 TM 1011; SOP52, WIF7
Thermal Shock  (-65 to 150) °C (Liquid to Liquid) 5 min dwell <10 s transfer	JESD22-A106; MIL-STD 883 TM 1011; SOP52, WIF22
Moisture Reflow Sensitivity  Bake 125 + (-0 to 5) °C 30 to 85) °C ± 2 °C (60 to 85) % ±3% RH	JEDEC J-STD-020; SOP52, WIF12
Preconditioning  Bake 125 + (-0 to 5) °C (30 to 85) °C ± 2 °C (60 to 85) ±3 %RH	JESD22-A113; SOP52, WIF12

<b><u>Test(s):</u></b>	<b><u>Test Method(s) <sup>1,2</sup>:</u></b>
<b><u>Optical</u></b>	
SEM - Scanning Electron Microscope (Defects Imaging)  EDX - Energy Dispersive X-ray Spectroscopy  Elements C to U; (5- 30) keV	SOP23, WI-F9, WI-F10, WI-F11; ASTM E766; MIL-STD 883, Method 2011; MIL-STD 883, Method 2018; MIL-STD 1580C, Requirement 9
Bond Shear Test  Royce Instruments 620;  SMS-250 g: Accuracy: $\pm 0.1\%$ gf Capacity: 250 gf Max  SMS-5K: Accuracy $\pm 0.1\%$ kgf Capacity: 5 kgf Max	JEDEC – JESD22-B117; JEDEC – JESD22-B116; AEC-Q100; SOP23, WIF6
Wire Pull Test  SMW-100g: Accuracy $\pm 0.1\%$ gf Capacity: 100 gf Max	MIL-STD-883 Method 2011; AEC-Q100; JEDEC - JESD22-B120; SOP23, WIF6

<sup>1</sup> Failure analysis performed using test methods listed.

<sup>2</sup> SOP's are accredited internal methods.



## Accredited Laboratory

A2LA has accredited

**EUROFINS EAG ENGINEERING SCIENCE, LLC**

*Irvine, CA*

for technical competence in the field of

**Electrical Testing**

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 28<sup>th</sup> day of March 2024.

A blue ink signature of Mr. Trace McInturff, written over a horizontal line.

Mr. Trace McInturff, Vice President, Accreditation Services  
For the Accreditation Council  
Certificate Number 2797.12  
Valid to February 28, 2026

*For the types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.*